**INFORMATION DISCLOSURE STATEMENT**

App. No. : Todd et al.  
Filed : 10/074,564  
For : February 11, 2002  
For : THIN FILMS AND METHODS OF  
MAKING THEM  
Examiner : Brook Kebede  
Group Art Unit : 2823

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

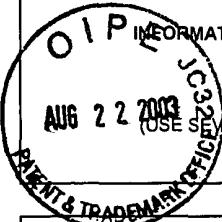
Enclosed is form PTO-1449 listing references that are also enclosed.

This Information Disclosure Statement is being filed before the receipt of a first Office Action on the merits, and presumably no fee is required in accordance with 37 C.F.R. § 1.97(b)(3). If a first Office Action on the merits was mailed before the mailing date of this Statement, the Commissioner is authorized to charge the fee set forth in 37 C.F.R. § 1.17(p) to Deposit Account No. 11-1410.

Respectfully submitted,  
KNOBBE, MARTENS, OLSON & BEAR, LLP

Dated: 8/19/03

By: Joseph J. Mallon  
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FORM PTO-1449  INFORMATION DISCLOSURE STATEMENT BY APPLICANT AUG 22 2002 (USE SEVERAL SHEETS IF NECESSARY)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. ASMEX.333A	APPLICATION NO. 10/074,564
		APPLICANT Todd et al.	
		FILING DATE February 11, 2002	GROUP 2823

U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
1.	5,214,002	05/25/93	Hayashi et al.			
2.	5,356,821	10/18/94	Naruse et al.			
3.	5,471,330	11/28/95	Sarma			
4.	6,103,600	08/15/00	Ueda et al.			

FOREIGN PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
						YES NO
5.	11317530	16-11-99	Japan (abstract)			X
6.	EP 0368651 A2	16-05-90				
7.	EP 0486047 A2	20-05-92				
8.	EP 0747974 A2	11-12-96				
9.	EP 1065728 A2	03-01-01				
10.	GB 2332564 A	23-06-99	United Kingdom			

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
11.	Olivares, J. et al.; "Solid-phase crystallization of amorphous SiGe films deposited by LPCVD on SiO <sub>2</sub> and glass," Thin Solid Films 337 (1999) pp. 51-54.

S:\DOCS\JOM\JOM-5151.DOC:081903

EXAMINER	DATE CONSIDERED
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.	